



Welcome to **E-XFL.COM**

Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	576
Number of Logic Elements/Cells	1368
Total RAM Bits	18432
Number of I/O	192
Number of Gates	30000
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	280-TFBGA, CSPBGA
Supplier Device Package	280-CSBGA (16x16)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs30xl-4cs280c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

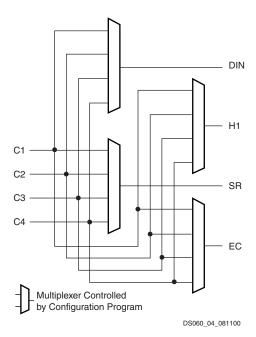


Figure 4: CLB Control Signal Interface

The four internal control signals are:

- EC: Enable Clock
- SR: Asynchronous Set/Reset or H function generator Input 0
- DIN: Direct In or H function generator Input 2
- H1: H function generator Input 1.

Input/Output Blocks (IOBs)

User-configurable input/output blocks (IOBs) provide the interface between external package pins and the internal logic. Each IOB controls one package pin and can be configured for input, output, or bidirectional signals. Figure 6 shows a simplified functional block diagram of the Spartan/XL FPGA IOB.

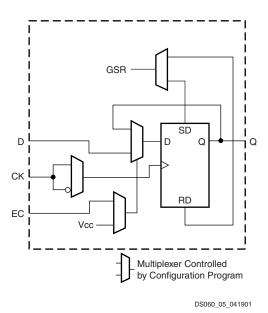


Figure 5: IOB Flip-Flop/Latch Functional Block
Diagram

IOB Input Signal Path

The input signal to the IOB can be configured to either go directly to the routing channels (via I1 and I2 in Figure 6) or to the input register. The input register can be programmed as either an edge-triggered flip-flop or a level-sensitive latch. The functionality of this register is shown in Table 3, and a simplified block diagram of the register can be seen in Figure 5.

Table 3: Input Register Functionality

Mode	CK	EC	D	Q
Power-Up or GSR	Х	Х	Х	SR
Flip-Flop		1*	D	D
	0	Х	Х	Q
Latch	1	1*	Х	Q
	0	1*	D	D
Both	Х	0	Х	Q

Legend:

X	Don't care.
^	
	Rising edge (clock not inverted).
SR	Set or Reset value. Reset is default.
0*	Input is Low or unconnected (default value)
1*	Input is High or unconnected (default value)



Table 4: Supported Sources for Spartan/XL Inputs

	-	artan outs	Spartan-XL Inputs
Source	5V, TTL	5V, CMOS	3.3V CMOS
Any device, V _{CC} = 3.3V, CMOS outputs	V	Unreli- able	V
Spartan family, V _{CC} = 5V, TTL outputs	√	Data	V
Any device, $V_{CC} = 5V$, TTL outputs $(V_{OH} \le 3.7V)$	√		V
Any device, V _{CC} = 5V, CMOS outputs	√	V	√ (default mode)

Spartan-XL Family V_{CC} Clamping

Spartan-XL FPGAs have an optional clamping diode connected from each I/O to V_{CC} . When enabled they clampringing transients back to the 3.3V supply rail. This clamping action is required in 3.3V PCI applications. V_{CC} clamping is a global option affecting all I/O pins.

Spartan-XL devices are fully 5V TTL I/O compatible if V_{CC} clamping is not enabled. With V_{CC} clamping enabled, the Spartan-XL devices will begin to clamp input voltages to one diode voltage drop above V_{CC} . If enabled, TTL I/O compatibility is maintained but full 5V I/O tolerance is sacrificed. The user may select either 5V tolerance (default) or 3.3V PCI compatibility. In both cases negative voltage is clamped to one diode voltage drop below ground.

Spartan-XL devices are compatible with TTL, LVTTL, PCI 3V, PCI 5V and LVCMOS signalling. The various standards are illustrated in Table 5.

Table 5: I/O Standards Supported by Spartan-XL FPGAs

Signaling Standard	VCC Clamping	Output Drive	V _{IH MAX}	V _{IH MIN}	V _{IL MAX}	V _{OH MIN}	V _{OL MAX}
TTL	Not allowed	12/24 mA	5.5	2.0	0.8	2.4	0.4
LVTTL	OK	12/24 mA	3.6	2.0	0.8	2.4	0.4
PCI5V	Not allowed	24 mA	5.5	2.0	0.8	2.4	0.4
PCI3V	Required	12 mA	3.6	50% of V _{CC}	30% of V _{CC}	90% of V _{CC}	10% of V _{CC}
LVCMOS 3V	OK	12/24 mA	3.6	50% of V _{CC}	30% of V _{CC}	90% of V _{CC}	10% of V _{CC}

Additional Fast Capture Input Latch (Spartan-XL Family Only)

The Spartan-XL family OB has an additional optional latch on the input. This latch is clocked by the clock used for the output flip-flop rather than the input clock. Therefore, two different clocks can be used to clock the two input storage elements. This additional latch allows the fast capture of input data, which is then synchronized to the internal clock by the IOB flip-flop or latch.

To place the Fast Capture latch in a design, use one of the special library symbols, ILFFX or ILFLX. ILFFX is a transparent-Low Fast Capture latch followed by an active High input flip-flop. ILFLX is a transparent Low Fast Capture latch followed by a transparent High input latch. Any of the clock inputs can be inverted before driving the library element, and the inverter is absorbed into the IOB.

IOB Output Signal Path

Output signals can be optionally inverted within the IOB, and can pass directly to the output buffer or be stored in an edge-triggered flip-flop and then to the output buffer. The functionality of this flip-flop is shown in Table 6.

Table 6: Output Flip-Flop Functionality

Mode	Clock	Clock Enable	Т	D	Q
Power-Up or GSR	Х	Х	0*	Х	SR
Flip-Flop	Х	0	0*	Х	Q
		1*	0*	D	D
	Х	Х	1	Х	Z
	0	Х	0*	Х	Q

Legend:

V	Don't care

___ Rising edge (clock not inverted).

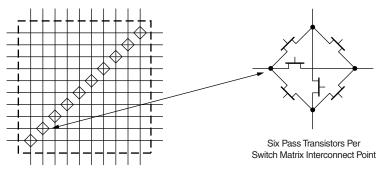
SR Set or Reset value. Reset is default.

0* Input is Low or unconnected (default value)

1* Input is High or unconnected (default value)

Z 3-state





DS060_10_081100

Figure 10: Programmable Switch Matrix

Double-Length Lines

The double-length lines consist of a grid of metal segments, each twice as long as the single-length lines: they run past two CLBs before entering a PSM. Double-length lines are grouped in pairs with the PSMs staggered, so that each line goes through a PSM at every other row or column of CLBs (see Figure 8).

There are four vertical and four horizontal double-length lines associated with each CLB. These lines provide faster signal routing over intermediate distances, while retaining routing flexibility.

Longlines

12

Longlines form a grid of metal interconnect segments that run the entire length or width of the array. Longlines are intended for high fan-out, time-critical signal nets, or nets that are distributed over long distances.

Each Spartan/XL device longline has a programmable splitter switch at its center. This switch can separate the line into two independent routing channels, each running half the width or height of the array.

Routing connectivity of the longlines is shown in Figure 8. The longlines also interface to some 3-state buffers which is described later in 3-State Long Line Drivers, page 19.

I/O Routing

Spartan/XL devices have additional routing around the IOB ring. This routing is called a VersaRing. The VersaRing facilitates pin-swapping and redesign without affecting board layout. Included are eight double-length lines, and four long-lines.

Global Nets and Buffers

The Spartan/XL devices have dedicated global networks. These networks are designed to distribute clocks and other high fanout control signals throughout the devices with minimal skew.

Four vertical longlines in each CLB column are driven exclusively by special global buffers. These longlines are in addition to the vertical longlines used for standard interconnect. In the 5V Spartan devices, the four global lines can be driven by either of two types of global buffers; Primary Global buffers (BUFGP) or Secondary Global buffers (BUFGS). Each of these lines can be accessed by one particular Primary Global buffer, or by any of the Secondary Global buffers, as shown in Figure 11. In the 3V Spartan-XL devices, the four global lines can be driven by any of the eight Global Low-Skew Buffers (BUFGLS). The clock pins of every CLB and IOB can also be sourced from local interconnect.



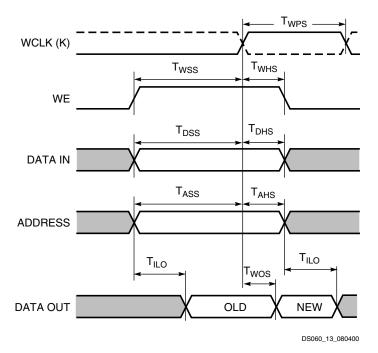


Figure 13: Data Write and Access Timing for RAM

WCLK can be configured as active on either the rising edge (default) or the falling edge. While the WCLK input to the RAM accepts the same signal as the clock input to the associated CLB's flip-flops, the sense of this WCLK input can be

inverted with respect to the sense of the flip-flop clock inputs. Consequently, within the same CLB, data at the RAM SPO line can be stored in a flip-flop with either the same or the inverse clock polarity used to write data to the RAM.

The WE input is active High and cannot be inverted within the CLB.

Allowing for settling time, the data on the SPO output reflects the contents of the RAM location currently addressed. When the address changes, following the asynchronous delay T_{ILO} , the data stored at the new address location will appear on SPO. If the data at a particular RAM address is overwritten, after the delay T_{WOS} , the new data will appear on SPO.

Dual-Port Mode

In dual-port mode, the function generators (F-LUT and G-LUT) are used to create a 16 x 1 dual-port memory. Of the two data ports available, one permits read and write operations at the address specified by A[3:0] while the second provides only for read operations at the address specified independently by DPRA[3:0]. As a result, simultaneous read/write operations at different addresses (or even at the same address) are supported.

The functional organization of the 16 \times 1 dual-port RAM is shown in Figure 14. The dual-port RAM signals and the

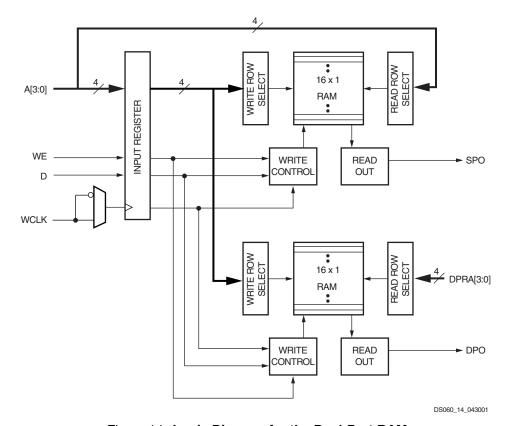


Figure 14: Logic Diagram for the Dual-Port RAM



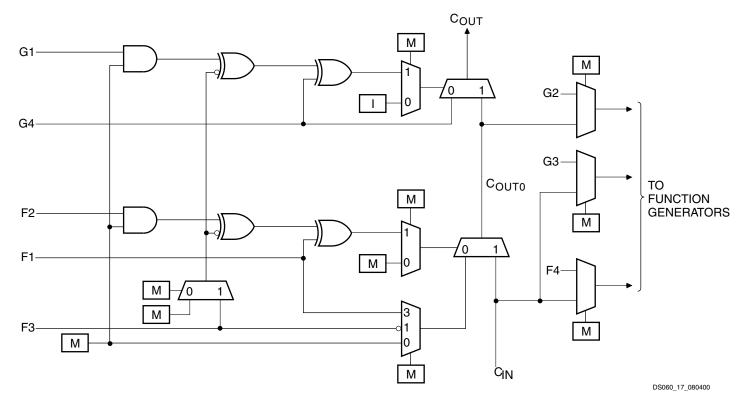


Figure 17: Detail of Spartan/XL Dedicated Carry Logic

3-State Long Line Drivers

A pair of 3-state buffers is associated with each CLB in the array. These 3-state buffers (BUFT) can be used to drive signals onto the nearest horizontal longlines above and below the CLB. They can therefore be used to implement multiplexed or bidirectional buses on the horizontal long-lines, saving logic resources.

There is a weak keeper at each end of these two horizontal longlines. This circuit prevents undefined floating levels. However, it is overridden by any driver.

The buffer enable is an active High 3-state (i.e., an active Low enable), as shown in Table 11.

Three-State Buffer Example

Figure 18 shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.

Pay particular attention to the polarity of the T pin when using these buffers in a design. Active High 3-state (T) is identical to an active Low output enable, as shown in Table 11.

Table 11: Three-State Buffer Functionality

IN	Т	OUT
X	1	Z
IN	0	IN

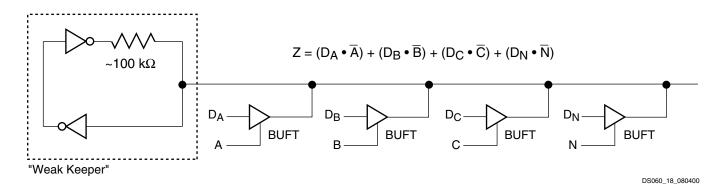


Figure 18: 3-state Buffers Implement a Multiplexer



Table 12: Boundary Scan Instructions

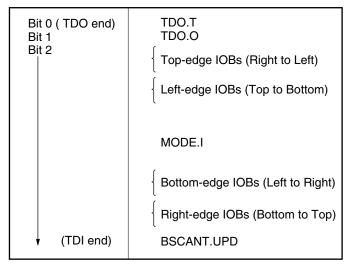
Ins	structi	on	Test	TDO	I/O Data
12	l1	10	Selected	Source	Source
0	0	0	EXTEST	DR	DR
0	0	1	SAMPLE/ PRELOAD	DR	Pin/Logic
0	1	0	USER 1	BSCAN. TDO1	User Logic
0	1	1	USER 2	BSCAN. TDO2	User Logic
1	0	0	READBACK	Readback Data	Pin/Logic
1	0	1	CONFIGURE	DOUT	Disabled
1	1	0	IDCODE (Spartan-XL only)	IDCODE Register	-
1	1	1	BYPASS	Bypass Register	-

Bit Sequence

The bit sequence within each IOB is: In, Out, 3-state. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contributes all three bits.

The first two bits in the I/O data register are TDO.T and TDO.O, which can be used for the capture of internal signals. The final bit is BSCANT.UPD, which can be used to drive an internal net. These locations are primarily used by Xilinx for internal testing.

From a cavity-up view of the chip (as shown in the FPGA Editor), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Figure 21. The device-specific pinout tables for the Spartan/XL devices include the boundary scan locations for each IOB pin.



DS060 21 080400

Figure 21: Boundary Scan Bit Sequence

BSDL (Boundary Scan Description Language) files for Spartan/XL devices are available on the Xilinx website in the File Download area. Note that the 5V Spartan devices and 3V Spartan-XL devices have different BSDL files.

Including Boundary Scan in a Design

If boundary scan is only to be used during configuration, no special elements need be included in the schematic or HDL code. In this case, the special boundary scan pins TDI, TMS, TCK and TDO can be used for user functions after configuration.

To indicate that boundary scan remain enabled after configuration, place the BSCAN library symbol and connect the TDI, TMS, TCK and TDO pad symbols to the appropriate pins, as shown in Figure 22.

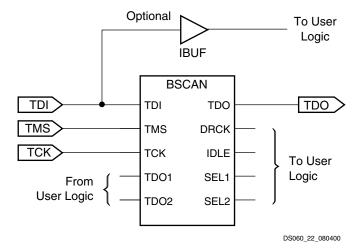


Figure 22: Boundary Scan Example



Master Serial Mode

The Master serial mode uses an internal oscillator to generate a Configuration Clock (CCLK) for driving potential slave devices and the Xilinx serial-configuration PROM (SPROM). The CCLK speed is selectable as either 1 MHz (default) or 8 MHz. Configuration always starts at the default slow frequency, then can switch to the higher frequency during the first frame. Frequency tolerance is –50% to +25%.

In Master Serial mode, the CCLK output of the device drives a Xilinx SPROM that feeds the FPGA DIN input. Each rising edge of the CCLK output increments the Serial PROM internal address counter. The next data bit is put on the SPROM data output, connected to the FPGA DIN pin. The FPGA accepts this data on the subsequent rising CCLK edge.

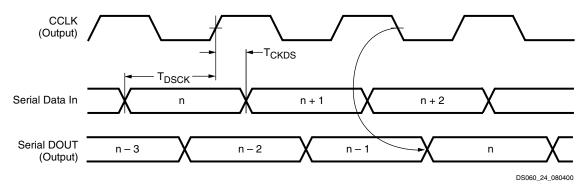
When used in a daisy-chain configuration the Master Serial FPGA is placed as the first device in the chain and is referred to as the lead FPGA. The lead FPGA presents the preamble data, and all data that overflows the lead device, on its DOUT pin. There is an internal pipeline delay of 1.5 CCLK periods, which means that DOUT changes on the

falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge. See the timing diagram in Figure 24.

In the bitstream generation software, the user can specify Fast Configuration Rate, which, starting several bits into the first frame, increases the CCLK frequency by a factor of eight. For actual timing values please refer to the specification section. Be sure that the serial PROM and slaves are fast enough to support this data rate. Earlier families such as the XC3000 series do not support the Fast Configuration Rate option.

The SPROM CE input can be driven from either $\overline{\text{LDC}}$ or DONE. Using $\overline{\text{LDC}}$ avoids potential contention on the DIN pin, if this pin is configured as user I/O, but $\overline{\text{LDC}}$ is then restricted to be a permanently High user output after configuration. Using DONE can also avoid contention on DIN, provided the Early DONE option is invoked.

Figure 25 shows a full master/slave system. The leftmost device is in Master Serial mode, all other devices in the chain are in Slave Serial mode.



	Symbol	Description	Min	Units
CCLK	T _{DSCK}	DIN setup	20	ns
COLK	T _{CKDS}	DIN hold	0	ns

Notes:

- 1. At power-up, V_{CC} must rise from 2.0V to V_{CC} min in less than 25 ms, otherwise delay configuration by pulling PROGRAM Low until V_{CC} is valid.
- Master Serial mode timing is based on testing in slave mode.

Figure 24: Master Serial Mode Programming Switching Characteristics

Slave Serial Mode

In Slave Serial mode, the FPGA receives serial configuration data on the rising edge of CCLK and, after loading its configuration, passes additional data out, resynchronized on the next falling edge of CCLK.

In this mode, an external signal drives the CCLK input of the FPGA (most often from a Master Serial device). The serial configuration bitstream must be available at the DIN input of the lead FPGA a short setup time before each rising CCLK edge.

The lead FPGA then presents the preamble data—and all data that overflows the lead device—on its DOUT pin. There is an internal delay of 0.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

Figure 25 shows a full master/slave system. A Spartan/XL device in Slave Serial mode should be connected as shown in the third device from the left.



to the DONE pin. User I/Os for each device become active after the DONE pin for that device goes High. (The exact timing is determined by development system options.) Since the DONE pin is open-drain and does not drive a High value, tying the DONE pins of all devices together prevents all devices in the chain from going High until the last device

in the chain has completed its configuration cycle. If the DONE pin of a device is left unconnected, the device becomes active as soon as that device has been configured. Only devices supporting Express mode can be used to form an Express mode daisy chain.

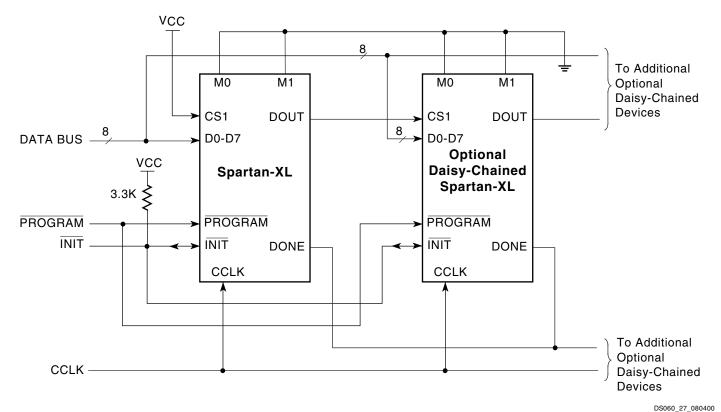


Figure 27: Express Mode Circuit Diagram



Table 16: Spartan/XL Data Stream Formats

Data Type	Serial Modes (D0)	Express Mode (D0-D7) (Spartan-XL only)
Fill Byte	11111111b	FFFFh
Preamble Code	0010b	11110010b
Length Count	COUNT[23:0]	COUNT[23:0] ⁽¹⁾
Fill Bits	1111b	-
Field Check Code	-	11010010b
Start Field	0b	11111110b ⁽²⁾
Data Frame	DATA[n-1:0]	DATA[n-1:0]
CRC or Constant Field Check	xxxx (CRC) or 0110b	11010010b
Extend Write Cycle	-	FFD2FFFFFh
Postamble	01111111b	-
Start-Up Bytes ⁽³⁾	FFh	FFFFFFFFFF

Legend:

Unshaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

Notes:

- 1. Not used by configuration logic.
- 2. 11111111b for XCS40XL only.
- 3. Development system may add more start-up bytes.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The Spartan-XL family Express mode only supports non-CRC error checking. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading before DONE goes High, and the pulling down of the $\overline{\text{INIT}}$ pin. In Master serial mode, CCLK continues to operate externally. The user must detect $\overline{\text{INIT}}$ and initialize a new configuration by pulsing the $\overline{\text{PROGRAM}}$ pin Low or cycling V_{CC} .

Cyclic Redundancy Check (CRC) for Configuration and Readback

The Cyclic Redundancy Check is a method of error detection in data transmission applications. Generally, the transmitting system performs a calculation on the serial bitstream. The result of this calculation is tagged onto the data stream as additional check bits. The receiving system performs an identical calculation on the bitstream and compares the result with the received checksum.

Each data frame of the configuration bitstream has four error bits at the end, as shown in Table 16. If a frame data error is detected during the loading of the FPGA, the configuration process with a potentially corrupted bitstream is terminated. The FPGA pulls the INIT pin Low and goes into a Wait state.



Table 17: Spartan/XL Program Data

Device	XC	CS05	XC	S10	XC	S20	XC	S30	XC	S40		
Max System Gates	5,	000	10	,000	20,000		30,000		40	,000		
CLBs (Row x Col.)		00 x 10)	_	96 x 14)	400 (20 x 20)				576 (24 x 24)		784 (28 x 28)	
IOBs		80	1	12	1	60	1	92	20)5 ⁽⁴⁾		
Part Number	XCS05	XCS05XL	XCS10	XCS10XL	XCS20	XCS20XL	XCS30	XCS30XL	XCS40	XCS40XL		
Supply Voltage	5V	3.3V	5V	3.3V	5V	3.3V	5V	3.3V	5V	3.3V		
Bits per Frame	126	127	166	167	226	227	266	267	306	307		
Frames	428	429	572	573	788	789	932	933	1,076	1,077		
Program Data	53,936	54,491	94,960	95,699	178,096	179,111	247,920	249,119	329,264	330,647		
PROM Size (bits)	53,984	54,544	95,008	95,752	178,144	179,160	247,968	249,168	329,312	330,696		
Express Mode PROM Size (bits)	-	79,072	-	128,488	-	221,056	-	298,696	-	387,856		

Notes:

- Bits per Frame = (10 x number of rows) + 7 for the top + 13 for the bottom + 1 + 1 start bit + 4 error check bits (+1 for Spartan-XL device)
 Number of Frames = (36 x number of columns) + 26 for the left edge + 41 for the right edge + 1 (+ 1 for Spartan-XL device)
 Program Data = (Bits per Frame x Number of Frames) + 8 postamble bits
 PROM Size = Program Data + 40 (header) + 8, rounded up to the nearest byte
- 2. The user can add more "1" bits as leading dummy bits in the header, or, if CRC = off, as trailing dummy bits at the end of any frame, following the four error check bits. However, the Length Count value must be adjusted for all such extra "one" bits, even for extra leading ones at the beginning of the header.
- 3. Express mode adds 57 (XCS05XL, XCS10XL), or 53 (XCS20XL, XCS30XL, XCS40XL) bits per frame, + additional start-up bits.
- 4. XCS40XL provided 224 max I/O in CS280 package discontinued by PDN2004-01.

During Readback, 11 bits of the 16-bit checksum are added to the end of the Readback data stream. The checksum is computed using the CRC-16 CCITT polynomial, as shown in Figure 29. The checksum consists of the 11 most significant bits of the 16-bit code. A change in the checksum indicates a change in the Readback bitstream. A comparison to a previous checksum is meaningful only if the readback

data is independent of the current device state. CLB outputs should not be included (Readback Capture option not used), and if RAM is present, the RAM content must be unchanged.

Statistically, one error out of 2048 might go undetected.



Readback Switching Characteristics Guidelines

The following guidelines reflect worst-case values over the recommended operating conditions.

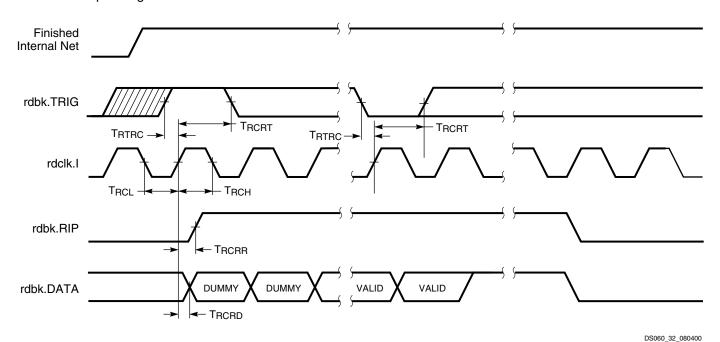


Figure 33: Spartan and Spartan-XL Readback Timing Diagram

Spartan and Spartan-XL Readback Switching Characteristics

Symbol		Description	Min	Max	Units
T _{RTRC}	rdbk.TRIG	rdbk.TRIG setup to initiate and abort Readback	200	-	ns
T _{RCRT}		rdbk.TRIG hold to initiate and abort Readback	50	-	ns
T _{RCRD}	rdclk.l	rdbk.DATA delay	-	250	ns
T _{RCRR}		rdbk.RIP delay	-	250	ns
T _{RCH}		High time	250	500	ns
T _{RCL}		Low time	250	500	ns

Notes:

- 1. Timing parameters apply to all speed grades.
- 2. If rdbk.TRIG is High prior to Finished, Finished will trigger the first Readback.



Spartan Family Detailed Specifications

Definition of Terms

In the following tables, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

Advance: Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or families. Values are subject to change. Use as estimates, not for production.

Preliminary: Based on preliminary characterization. Further changes are not expected.

Unmarked: Specifications not identified as either Advance or Preliminary are to be considered Final.

Notwithstanding the definition of the above terms, all specifications are subject to change without notice.

Except for pin-to-pin input and output parameters, the AC parameter delay specifications included in this document are derived from measuring internal test patterns. All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications.

Spartan Family Absolute Maximum Ratings(1)

Symbol	Description	Value	Units	
V _{CC}	Supply voltage relative to GND	-0.5 to +7.0	V	
V _{IN}	Input voltage relative to GND ^(2,3)	Input voltage relative to GND ^(2,3)		
V _{TS}	Voltage applied to 3-state output ^(2,3)		-0.5 to V _{CC} +0.5	V
T _{STG}	Storage temperature (ambient)	-65 to +150	°C	
T _J	Junction temperature Plastic packages		+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress
 ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions
 is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.
- 2. Maximum DC overshoot (above V_{CC}) or undershoot (below GND) must be limited to either 0.5V or 10 mA, whichever is easier to achieve.
- 3. Maximum AC (during transitions) conditions are as follows; the device pins may undershoot to -2.0V or overshoot to +7.0V, provided this overshoot or undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
- 4. For soldering guidelines, see the Package Information on the Xilinx website.

Spartan Family Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V _{CC}	Supply voltage relative to GND, T _J = 0°C to +85°C	Commercial	4.75	5.25	V
	Supply voltage relative to GND, $T_J = -40^{\circ}\text{C}$ to $+100^{\circ}\text{C}^{(1)}$	Industrial	4.5	5.5	V
V _{IH}	High-level input voltage ⁽²⁾	TTL inputs	2.0	V_{CC}	V
		CMOS inputs	70%	100%	V_{CC}
V _{IL}	Low-level input voltage ⁽²⁾	TTL inputs	0	8.0	V
		CMOS inputs	0	20%	V_{CC}
T _{IN}	Input signal transition time	1	-	250	ns

Notes:

- At junction temperatures above those listed as Recommended Operating Conditions, all delay parameters increase by 0.35% per °C.
- 2. Input and output measurement thresholds are: 1.5V for TTL and 2.5V for CMOS.



Capacitive Load Factor

Figure 34 shows the relationship between I/O output delay and load capacitance. It allows a user to adjust the specified output delay if the load capacitance is different than 50 pF. For example, if the actual load capacitance is 120 pF, add 2.5 ns to the specified delay. If the load capacitance is 20 pF, subtract 0.8 ns from the specified output delay. Figure 34 is usable over the specified operating conditions of voltage and temperature and is independent of the output slew rate control.

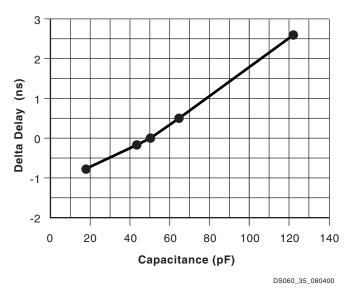


Figure 34: Delay Factor at Various Capacitive Loads



Spartan-XL Family Global Buffer Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

When fewer vertical clock lines are connected, the clock distribution is faster; when multiple clock lines per column are driven from the same global clock, the delay is longer. For

more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

			Speed Grade		
			-5	-4	
Symbol	Description	Device	Max	Max	Units
T _{GLS}	From pad through buffer, to any clock K	XCS05XL	1.4	1.5	ns
		XCS10XL	1.7	1.8	ns
		XCS20XL	2.0	2.1	ns
		XCS30XL	2.3	2.5	ns
		XCS40XL	2.6	2.8	ns



Spartan-XL Family Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case oper-

ating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

Spartan-XL Family Setup and Hold

			Speed Grade		
			-5	-4	
Symbol	Description	Device	Max	Max	Units
Input Setup/H	old Times Using Global Clock and IFF				
T _{SUF} /T _{HF}	No Delay	XCS05XL	1.1/2.0	1.6/2.6	ns
		XCS10XL	1.0/2.2	1.5/2.8	ns
		XCS20XL	0.9/2.4	1.4/3.0	ns
		XCS30XL	0.8/2.6	1.3/3.2	ns
		XCS40XL	0.7/2.8	1.2/3.4	ns
T _{SU} /T _H	Full Delay	XCS05XL	3.9/0.0	5.1/0.0	ns
		XCS10XL	4.1/0.0	5.3/0.0	ns
		XCS20XL	4.3/0.0	5.5/0.0	ns
		XCS30XL	4.5/0.0	5.7/0.0	ns
		XCS40XL	4.7/0.0	5.9/0.0	ns

Notes:

- 1. IFF = Input Flip-Flop or Latch
- 2. Setup time is measured with the fastest route and the lightest load. Hold time is measured using the furthest distance and a reference load of one clock pin per IOB/CLB.

Capacitive Load Factor

Figure 35 shows the relationship between I/O output delay and load capacitance. It allows a user to adjust the specified output delay if the load capacitance is different than 50 pF. For example, if the actual load capacitance is 120 pF, add 2.5 ns to the specified delay. If the load capacitance is 20 pF, subtract 0.8 ns from the specified output delay. Figure 35 is usable over the specified operating conditions of voltage and temperature and is independent of the output slew rate control.

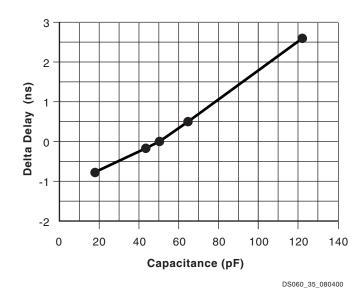


Figure 35: Delay Factor at Various Capacitive Loads



Spartan-XL Family IOB Input Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

				Speed	Grade		
			-	5	-	4	
Symbol	Description	Device	Min	Max	Min	Max	Units
Setup Tim	es						
T _{ECIK}	Clock Enable (EC) to Clock (IK)	All devices	0.0	-	0.0	-	ns
T _{PICK}	Pad to Clock (IK), no delay	All devices	1.0	-	1.2	-	ns
T _{POCK}	Pad to Fast Capture Latch Enable (OK), no delay	All devices	0.7	-	0.8	-	ns
Hold Time	es				•		
	All Hold Times	All devices	0.0	-	0.0	-	ns
Propagati	on Delays				•		
T _{PID}	Pad to I1, I2	All devices	-	0.9	-	1.1	ns
T _{PLI}	Pad to I1, I2 via transparent input latch, no delay	All devices	-	2.1	-	2.5	ns
T _{IKRI}	Clock (IK) to I1, I2 (flip-flop)	All devices	-	1.0	-	1.1	ns
T _{IKLI}	Clock (IK) to I1, I2 (latch enable, active Low)	All devices	-	1.1	-	1.2	ns
Delay Add	ler for Input with Full Delay Option				•		
T _{Delay}	$T_{PICKD} = T_{PICK} + T_{Delay}$	XCS05XL	4.0	-	4.7	-	ns
	$T_{PDLI} = T_{PLI} + T_{Delay}$	XCS10XL	4.8	-	5.6	-	ns
		XCS20XL	5.0	-	5.9	-	ns
		XCS30XL	5.5	-	6.5	-	ns
		XCS40XL	6.5	-	7.6	-	ns
Global Se	t/Reset	"		ı	1	ı	i.
T _{MRW}	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns
T _{RRI}	Delay from GSR input to any Q	XCS05XL	-	9.0	-	10.5	ns
		XCS10XL	-	9.5	-	11.0	ns
		XCS20XL	-	10.0	-	11.5	ns
		XCS30XL	-	11.0	-	12.5	ns
		XCS40XL	-	12.0	-	13.5	ns

Notes:

- 1. Input pad setup and hold times are specified with respect to the internal clock (IK). For setup and hold times with respect to the clock input, see the pin-to-pin parameters in the Pin-to-Pin Input Parameters table.
- 2. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.



XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84 ⁽⁴⁾	VQ100	CS144 ^(2,4)	TQ144	Bndry Scan
I/O	P80	P81	A10	P116	17
GND	-	-	C9	P118	-
I/O	-	-	B9	P119	20
I/O	-	-	A9	P120	23
I/O	P81	P82	D8	P121	26
I/O	P82	P83	C8	P122	29
I/O	-	P84	B8	P123	32
I/O	-	P85	A8	P124	35
I/O	P83	P86	B7	P125	38
I/O	P84	P87	A7	P126	41
GND	P1	P88	C7	P127	-

Notes:

- 1. 5V Spartan family only
- 2. 3V Spartan-XL family only
- 3. The "PWRDWN" on the XCS10XL is not part of the Boundary Scan chain. For the XCS10XL, subtract 1 from all Boundary Scan numbers from GCK3 on (175 and higher).
- 4. PC84 and CS144 packages discontinued by PDN2004-01

Additional XCS10/XL Package Pins

TQ144								
	Not Connected Pins							
P117	-	-	-	-	-			
5/5/97	5/5/97							

CS144								
	Not Connected Pins							
D9	-	-	-	-	-			
4/28/99	4/28/99							

XCS20 and XCS20XL Device Pinouts

XCS20/XL					Bndry
Pad Name	VQ100	CS144 ^(2,4)	TQ144	PQ208	Scan
VCC	P89	D7	P128	P183	-
I/O	P90	A6	P129	P184	62
I/O	P91	B6	P130	P185	65
I/O	P92	C6	P131	P186	68
I/O	P93	D6	P132	P187	71
I/O	-	-	-	P188	74
I/O	-	-	-	P189	77
I/O	P94	A5	P133	P190	80
I/O	P95	B5	P134	P191	83
VCC ⁽²⁾	-	-	-	P192	-
I/O	-	C5	P135	P193	86
I/O	-	D5	P136	P194	89
GND	-	A4	P137	P195	-
I/O	-	-	-	P196	92
I/O	-	-	-	P197	95
I/O	-	-	-	P198	98
I/O	-	-	-	P199	101
I/O	P96	B4	P138	P200	104
I/O	P97	C4	P139	P201	107
I/O	-	А3	P140	P204	110
I/O	-	B3	P141	P205	113
I/O	P98	C3	P142	P206	116

XCS20 and XCS20XL Device Pinouts

XCS20/XL	V0400	CS144 ^(2,4)	TO444	DOGGG	Bndry
Pad Name	VQ100		TQ144	PQ208	Scan
I/O, SGCK1 ⁽¹⁾ , GCK8 ⁽²⁾	P99	A2	P143	P207	119
VCC	P100	B2	P144	P208	-
GND	P1	A1	P1	P1	-
I/O, PGCK1 ⁽¹⁾ , GCK1 ⁽²⁾	P2	B1	P2	P2	122
I/O	P3	C2	P3	P3	125
I/O	-	C1	P4	P4	128
I/O	-	D4	P5	P5	131
I/O, TDI	P4	D3	P6	P6	134
I/O, TCK	P5	D2	P7	P7	137
I/O	-	-	-	P8	140
I/O	-	-	-	P9	143
I/O	-	-	-	P10	146
I/O	-	-	-	P11	149
GND	-	D1	P8	P13	-
I/O	-	E4	P9	P14	152
I/O	-	E3	P10	P15	155
I/O, TMS	P6	E2	P11	P16	158
I/O	P7	E1	P12	P17	161
VCC ⁽²⁾	-	-	-	P18	-
I/O	-	-	-	P19	164
I/O	-	-	-	P20	167



XCS30 and XCS30XL Device Pinouts (Continued)

XCS30/XL Pad Name	VQ100 ⁽⁵⁾	TQ144	PQ208	PQ240	BG256 ⁽⁵⁾	CS280 ^(2,5)	Bndry Scan
I/O	-	P5	P5	P5	D3	C1	155
I/O, TDI	P4	P6	P6	P6	E4	D4	158
I/O, TCK	P5	P7	P7	P7	C1	D3	161
I/O	-	-	P8	P8	D1	E2	164
I/O	-	-	P9	P9	E3	E4	167
I/O	-	-	P10	P10	E2	E1	170
I/O	-	-	P11	P11	E1	F5	173
I/O	-	-	P12	P12	F3	F3	176
I/O	-	-	-	P13	F2	F2	179
GND	-	P8	P13	P14	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O	-	P9	P14	P15	G3	F4	182
I/O	-	P10	P15	P16	G2	F1	185
I/O, TMS	P6	P11	P16	P17	G1	G3	188
I/O	P7	P12	P17	P18	НЗ	G2	191
VCC	-	-	P18	P19	VCC ⁽⁴⁾	G1	-
I/O	-	-	-	P20	H2	G4	194
I/O	-	-	-	P21	H1	H1	197
I/O	-	-	P19	P23	J2	H4	200
I/O	-	-	P20	P24	J1	J1	203
I/O	-	P13	P21	P25	K2	J2	206
I/O	P8	P14	P22	P26	K3	J3	209
I/O	P9	P15	P23	P27	K1	J4	212
I/O	P10	P16	P24	P28	L1	K1	215
GND	P11	P17	P25	P29	GND ⁽⁴⁾	GND ⁽⁴⁾	-
VCC	P12	P18	P26	P30	VCC ⁽⁴⁾	K2	-
I/O	P13	P19	P27	P31	L2	K3	218
I/O	P14	P20	P28	P32	L3	K4	221
I/O	P15	P21	P29	P33	L4	K5	224
I/O	-	P22	P30	P34	M1	L1	227
I/O	-	-	P31	P35	M2	L2	230
I/O	-	-	P32	P36	M3	L3	233
I/O	-	-	-	P38	N1	M2	236
I/O	-	-	-	P39	N2	M3	239
VCC	-	-	P33	P40	VCC ⁽⁴⁾	M4	-
I/O	P16	P23	P34	P41	P1	N1	242
I/O	P17	P24	P35	P42	P2	N2	245
I/O	-	P25	P36	P43	R1	N3	248
I/O	-	P26	P37	P44	P3	N4	251
GND	-	P27	P38	P45	GND ⁽⁴⁾	GND ⁽⁴⁾	-
1/0	-	-	-	P46	T1	P1	254
I/O	_	_	P39	P47	R3	P2	257
I/O	_	-	P40	P48	T2	P3	260
I/O	-	-	P41	P49	U1	P4	263
I/O	-	-	P42	P50	T3	P5	266
., 🔾			174	P51	U2	R1	269



CS280

VCC Pins							
E5	E7	E8	E9	E11	E12		
E13	G5	G15	H5	H15	J5		
J15	L5	L15	M5	M15	N5		
N15	R7	R8	R9	R11	R12		
R13	-	-	-	-	-		
	Not Connected Pins						
A4	A12	C8	C12	C15	D1		
D2	D5	D8	D17	D18	E15		
H2	НЗ	H18	H19	L4	M1		
M16	M18	R2	R4	R5	R15		
R17	T8	T15	U5	V8	V12		
W12	W16	-	-	-	-		
Not Connected Pins (VCC in XCS40XL)							
B5	B15	E3	E18	R3	R18		
V5	V15	-	-	-	-		

5/21/02

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280 ^(2,5)	Bndry Scan
VCC	P183	P212	VCC ⁽⁴⁾	VCC ⁽⁴⁾	Juli
					-
I/O	P184	P213	C10	D10	86
I/O	P185	P214	D10	E10	89
I/O	P186	P215	A9	A9	92
I/O	P187	P216	B9	B9	95
I/O	P188	P217	C9	C9	98
I/O	P189	P218	D9	D9	101
I/O	P190	P220	A8	A8	104
I/O	P191	P221	B8	B8	107
I/O	-	-	C8	C8	110
I/O	-	-	A7	D8	113
VCC	P192	P222	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
I/O	-	P223	A6	B7	116
I/O	-	P224	C7	C7	119
I/O	P193	P225	B6	D7	122
I/O	P194	P226	A5	A6	125
GND	P195	P227	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O	P196	P228	C6	B6	128
I/O	P197	P229	B5	C6	131
I/O	P198	P230	A4	D6	134
I/O	P199	P231	C5	E6	137

XCS40 and XCS40XL Device Pinouts

XCS40/XL	1 XOO+	ONL DO	741001		Bndry
Pad Name	PQ208	PQ240	BG256	CS280 ^(2,5)	Scan
I/O	P200	P232	B4	A5	140
I/O	P201	P233	A3	C5	143
I/O	-	1	-	D5	146
I/O	-	1	-	A4	149
I/O	P202	P234	D5	B4	152
I/O	P203	P235	C4	C4	155
I/O	P204	P236	В3	A3	158
I/O	P205	P237	B2	A2	161
I/O	P206	P238	A2	В3	164
I/O, SGCK1 ⁽¹⁾ , GCK8 ⁽²⁾	P207	P239	C3	B2	167
VCC	P208	P240	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
GND	P1	P1	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O, PGCK1 ⁽¹⁾ , GCK1 ⁽²⁾	P2	P2	B1	C3	170
I/O	P3	P3	C2	C2	173
I/O	P4	P4	D2	B1	176
I/O	P5	P5	D3	C1	179
I/O, TDI	P6	P6	E4	D4	182
I/O, TCK	P7	P7	C1	D3	185
I/O	-	-	-	D2	188
I/O	-	-	-	D1	191
I/O	P8	P8	D1	E2	194
I/O	P9	P9	E3	E4	197
I/O	P10	P10	E2	E1	200
I/O	P11	P11	E1	F5	203
I/O	P12	P12	F3	F3	206
I/O	-	P13	F2	F2	209
GND	P13	P14	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O	P14	P15	G3	F4	212
I/O	P15	P16	G2	F1	215
I/O, TMS	P16	P17	G1	G3	218
I/O	P17	P18	НЗ	G2	221
VCC	P18	P19	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
I/O	-	P20	H2	G4	224
I/O	-	P21	H1	H1	227
I/O	-	-	J4	H3	230
I/O	-	-	J3	H2	233
I/O	P19	P23	J2	H4	236
I/O	P20	P24	J1	J1	239
I/O	P21	P25	K2	J2	242
I/O	P22	P26	K3	J3	245
I/O	P23	P27	K1	J4	248
I/O	P24	P28	L1	K1	251



Revision History

The following table shows the revision history for this document.

Date	Version	Description
11/20/98	1.3	Added Spartan-XL specs and Power Down.
01/06/99	1.4	All Spartan-XL -4 specs designated Preliminary with no changes.
03/02/00	1.5	Added CS package, updated Spartan-XL specs to Final.
09/19/01	1.6	Reformatted, updated power specs, clarified configuration information. Removed T_{SOL} soldering information from Absolute Maximum Ratings table. Changed Figure 26: Slave Serial Mode Characteristics: T_{CCH} , T_{CCL} from 45 to 40 ns. Changed Master Mode Configuration Switching Characteristics: T_{CCLK} min. from 80 to 100 ns. Added Total Dist. RAM Bits to Table 1; added Start-Up, page 36 characteristics.
06/27/02	1.7	Clarified Express Mode pseudo daisy chain. Added new Industrial options. Clarified XCS30XL CS280 V _{CC} pinout.
06/26/08	1.8	Noted that PC84, CS144, and CS280 packages, and VQ100 and BG256 packages for XCS30 only, are discontinued by PDN2004-01. Extended description of recommended maximum delay of reconfiguration in Delaying Configuration After Power-Up, page 35. Added reference to Pb-free package options and provided link to Package Specifications, page 81. Updated links.
03/01/13	2.0	The products listed in this data sheet are obsolete. See XCN11010 for further information.